Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/684,466	CHANG, HYUK	
Examiner	**Art Unit**	
Julian Mercado	1745	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
PGPub	Search	9/5/07	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
See attached	9/6/07	